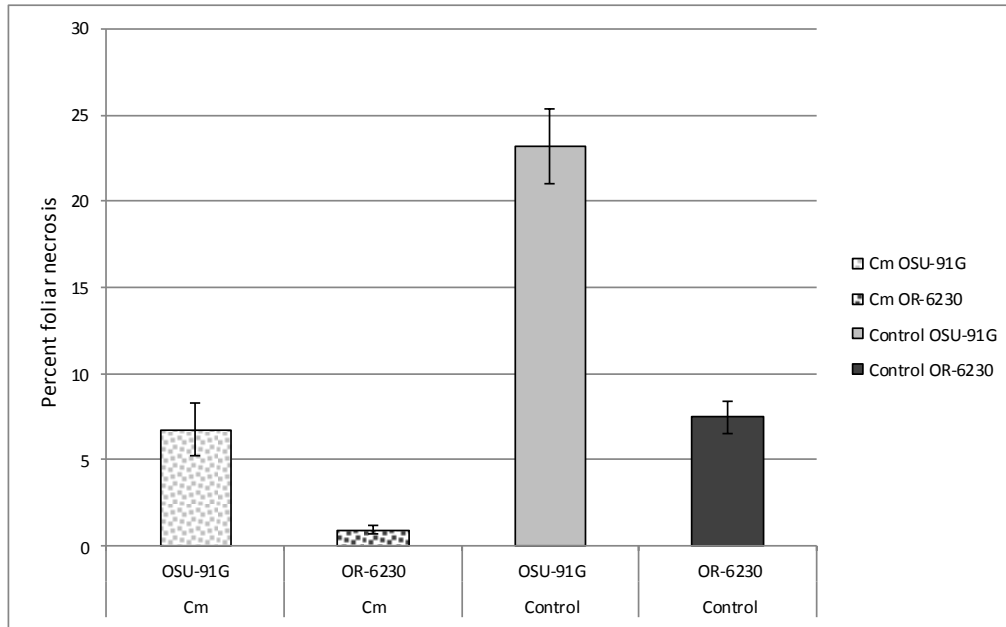
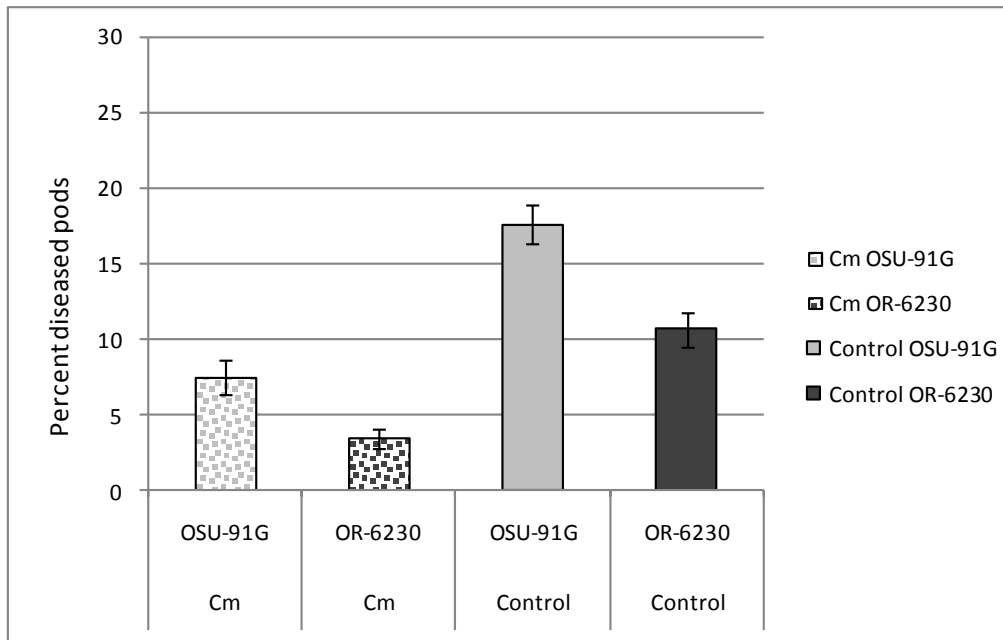


Experiment D.



Effect of *Cm* application and plant resistance on foliar white mold severity.



Effect of *Cm* application and plant resistance on pod white mold incidence.

At harvest, pod white mold incidence in the control fields was approximately 17 and 11% in 91G and OR-6230, respectively, and 7 and 3%, respectively, in the *Cm* treatment fields. Pod disease incidence was 37% lower in 6230 than in 91G in the control fields and 60% lower in OR-6230 than in 91G in the *Cm*-treated fields. The

lowest pod disease incidence was observed in the OR-6230 plants grown in *Cm*-treated fields (Fig. 4).

Bean marketable yields were not significantly different in the *Cm* and the control treatments ($p = 0.16$), but OR-6230 yielded less than 91G ($p < 0.001$) in both *Cm* and control fields (Fig.5).